

FEATURES

- Full Four Quadrant Multiplication
- 12-Bit Resolution
- Gain Error Tempco (2 ppm/C max.)
- Latch-Up Free
- Single +5 V to +15 V Supply
- Use MP7545B for New Designs
- TTL/15 V VMOS Compatible

APPLICATIONS

- Industrial Automation
- Automatic Test Equipment
- Disk Drive Servo Systems
- Digital/Synchro Conversion
- Programmable Gain Amplifiers
- Ratiometric A/D Conversion
- Function Generation
- Digitally Controlled Filters

GENERAL DESCRIPTION

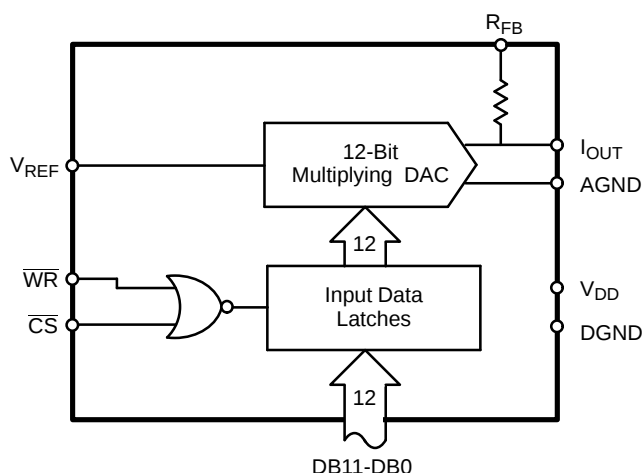
The MP7545 is a 12-bit CMOS multiplying Digital-to-Analog Converter with on-board data latches. It is loaded by a single 12-bit wide word and interfaces directly to most 12- and 16-bit bus systems. Data is loaded into the input latches under the control of the $\overline{CS}$ and $\overline{WR}$ inputs; tying these control inputs low

makes the input latches transparent allowing direct unbuffered operation of the DAC.

The MP7545 is particularly suitable for single supply operation and applications with wide temperature variations.

The MP7545 can be used with any supply voltage from +5 V to +15 V. With CMOS logic levels at the inputs the device dissipates less than 0.5 mW for $V_{DD} = +5$ V.

SIMPLIFIED BLOCK DIAGRAM



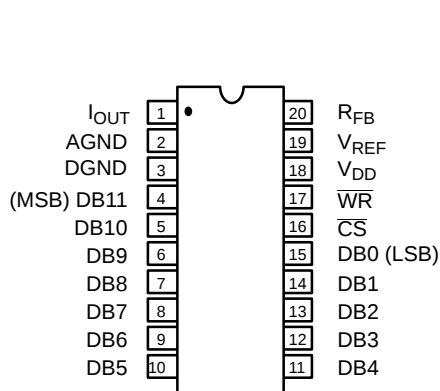
ORDERING INFORMATION

Package Type	Temperature Range	Part No.	INL (LSB)	DNL (LSB)	Gain Error (LSB)
Plastic Dip	-40 to +85°C	MP7545JN	+2	+4	+20
Plastic Dip	-40 to +85°C	MP7545KN	+1	+1	+10
Plastic Dip	-40 to +85°C	MP7545LN	+1/2	+1	+5
SOIC	-40 to +85°C	MP7545JS	+2	+4	+20
SOIC	-40 to +85°C	MP7545KS	+1	+1	+10
SOIC	-40 to +85°C	MP7545LS	+1/2	+1	+5
PLCC	-40 to +85°C	MP7545JP	+2	+4	+20
PLCC	-40 to +85°C	MP7545KP	+1	+1	+10
PLCC	-40 to +85°C	MP7545LP	+1/2	+1	+5
Ceramic Dip	-40 to +85°C	MP7545AD	+2	+4	+20
Ceramic Dip	-40 to +85°C	MP7545BD	+1	+1	+10
Ceramic Dip	-40 to +85°C	MP7545CD	+1/2	+1	+5
Ceramic Dip	-55 to +125°C	MP7545SD*	+2	+4	+20
Ceramic Dip	-55 to +125°C	MP7545TD*	+1	+1	+10

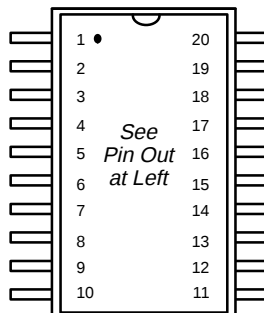
*Contact factory for non-compliant military processing

PIN CONFIGURATIONS

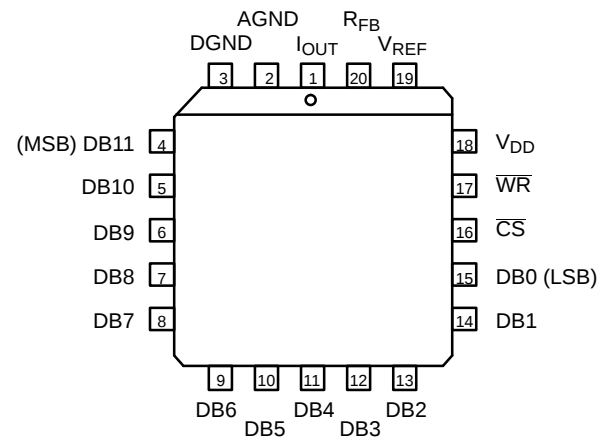
See Packaging Section for Package Dimensions



20 Pin CDIP, PDIP (0.300")
D20, N20



20 Pin SOIC (Jedec, 0.300") – S20
20 Pin SSOP – A20



20 Pin PLCC
P20

PIN OUT DEFINITIONS

PIN NO.	NAME	DESCRIPTION
1	I _{OUT}	Output Current
2	AGND	Analog Ground
3	DGND	Digital Ground
4	DB11	Data Input Bit 11 (MSB)
5	DB10	Data Input Bit 10
6	DB9	Data Input Bit 9
7	DB8	Data Input Bit 8
8	DB7	Data Input Bit 7
9	DB6	Data Input Bit 6
10	DB5	Data Input Bit 5
11	DB4	Data Input Bit 4
12	DB3	Data Input Bit 3
13	DB2	Data Input Bit 2
14	DB1	Data Input Bit 1
15	DB0	Data Input Bit 0 (LSB)
16	$\overline{CS}$	Chip Select (Active Low)
17	$\overline{WR}$	Write (Active Low)
18	V _{DD}	Digital Supply Voltage
19	V _{REF}	Reference Input
20	R _{FB}	Feedback Resistor

ELECTRICAL CHARACTERISTICS

(V_{DD} = + 5 V, V_{REF} = +10 V unless otherwise noted)

Parameter	Symbol	Min	25°C Typ	Max	Tmin to Tmax Min	Max	Units	Test Conditions/Comments
STATIC PERFORMANCE ¹								
Resolution (All Grades)	N	12			12		Bits	Best Fit Straight Line Spec. (Max INL – Min INL) / 2
Integral Non-Linearity (Relative Accuracy)	INL						LSB	
J, A, S				+2		+2		
K, B, T				+1		+1		
L, C				+1/2		+1/2		
Differential Non-Linearity	DNL						LSB	Using Internal R _{FB}
J, A, S				+4		+4		
K, B, T				+1		+1		
L, C				+1		+1		
Gain Error	GE						LSB	
J, A, S				±20		±20		ΔGain/ΔTemperature
K, B, T				±10		±10		
L, C				±5		±5		
Gain Temperature Coefficient ²	TC _{GE}					±2	ppm/°C	ΔGain/ΔTemperature
Power Supply Rejection Ratio	PSRR			±50		±100	ppm/%	ΔGain/ΔV _{DD} ΔV _{DD} = ± 5%
Output Leakage Current	I _{OUT}						nA	
J, K, L				±10		±50		
A, B, C				±10		±50		
S, T				±10		±200		
DYNAMIC PERFORMANCE ²								
Current Settling Time	t _S			2		2	μs	R _L =100Ω, C _L =13pF Full Scale Change to 1/2 LSB V _{REF} = 10kHz, 20 Vp-p sinewave. From 50% of digital input to 90% of final analog output current
AC Feedthrough at I _{OUT}	F _T		5				mV p-p	
Propagation Delay	t _{PD}			300			ns	
REFERENCE INPUT								
Input Resistance	R _{IN}	7		25	7	25	kΩ	
DIGITAL INPUTS ³								
Logical “1” Voltage	V _{IH}	2.4			2.4		V	
Logical “0” Voltage	V _{IL}			0.8		0.8	V	
Input Leakage Current	I _{LKG}			±1		±10	μA	
Input Capacitance ²								
Data	C _{IN}			5		5	pF	
Control	C _{IN}			20		20	pF	

ELECTRICAL CHARACTERISTICS (CONT'D)

Parameter	Symbol	Min	25°C Typ	Max	Tmin to Tmax Min	Max	Units	Test Conditions/Comments
ANALOG OUTPUTS								
Output Capacitance ²	C _{OUT} C _{OUT}			200 70		200 70	pF pF	DAC Inputs all 1's DAC Inputs all 0's
POWER SUPPLY⁵								
Functional Voltage Range	V _{DD}	5		15	5	15	V	All digital inputs = 0 V or V _{DD}
Supply Current	I _{DD}			2		2	mA	
SWITCHING CHARACTERISTICS^{2, 4}								
Chip Select to Write Set-Up Time	t _{CS}	280	200		380	270 typ	ns	
Chip Select to Write Hold Time	t _{CH}	0			0		ns	
Data Valid to Write Set-Up Time	t _{DS}	140	100		210	150 typ	ns	
Data Valid to Write Hold Time	t _{DH}	10			10		ns	
Write Pulse Width	t _{WR}	250	175		400	280 typ	ns	

NOTES:

- 1 Full Scale Range (FSR) is 10V for unipolar mode.
- 2 Guaranteed but not production tested.
- 3 Digital input levels should not go below ground or exceed the positive supply voltage, otherwise damage may occur.
- 4 See timing diagram.
- 5 Specified values guarantee functionality. Refer to other parameters for accuracy.

Specifications are subject to change without notice

ELECTRICAL CHARACTERISTICS

($V_{DD} = +15\text{ V}$, $V_{REF} = +10\text{ V}$ unless otherwise noted)

Parameter	Symbol	25°C			Tmin to Tmax		Units	Test Conditions/Comments
		Min	Typ	Max	Min	Max		
STATIC PERFORMANCE ¹								
Resolution (All Grades)	N	12			12		Bits	Best Fit Straight Line Spec. (Max INL – Min INL) / 2
Integral Non-Linearity (Relative Accuracy)	INL						LSB	
J, A, S				±2		±2		
K, B, T				±1		±1		
L, C				±1/2		±1/2		
Differential Non-Linearity	DNL						LSB	Using Internal R _{FB}
J, A, S				±4		±4		
K, B, T				±1		±1		
L, C				±1		±1		
Gain Error	GE						LSB	
J, A, S				±25		±25		ΔGain/ΔTemperature
K, B, T				±15		±15		
L, C				±10		±10		
Gain Temperature Coefficient ²	TC _{GE}					±2	ppm/°C	
Power Supply Rejection Ratio	PSRR			±50		±100	ppm/%	
Output Leakage Current	I _{OUT}						nA	ΔGain/ΔV _{DD} ΔV _{DD} = ± 5%
J, K, L				±10		±50		
A, B, C				±10		±50		
S, T				±10		±200		
DYNAMIC PERFORMANCE ²								
Current Settling Time	t _S			2		2	μs	Full Scale Change to 1/2 LSB V _{REF} = 10kHz, 20 Vp-p sinewave. V _{REF} = AGND From 50% of digital input to 90% of final analog output current
AC Feedthrough at I _{OUT}	F _T		5				mV p-p	
Glitch Energy	E _{gl}		250				nVs	
Propagation Delay	t _{PD}			250			ns	
REFERENCE INPUT								
Input Resistance	R _{IN}	7		25	7	25	kΩ	
DIGITAL INPUTS ³								
Logical “1” Voltage	V _{IH}	13.5			13.5		V	V _{IN} = 0 or V _{DD}
Logical “0” Voltage	V _{IL}			1.5		1.5	V	
Input Leakage Current	I _{LKG}			±1		±10	μA	
Input Capacitance ²								
DB0-DB11	C _{IN}			5		5	pF	
WR, CS	C _{IN}			20		20	pF	V _{IN} = 0

ELECTRICAL CHARACTERISTICS (CONT'D)

Parameter	Symbol	Min	25°C Typ	Max	Tmin to Tmax Min Max	Units	Test Conditions/Comments
ANALOG OUTPUTS							
Output Capacitance ²	C _{OUT} C _{OUT}			200 70	200 70	pF pF	DAC Inputs all 1's DAC Inputs all 0's
POWER SUPPLY⁵							
Functional Voltage Range Supply Current	V _{DD} I _{DD}	5		15 2	5 15 2 2	V mA	All digital inputs = 0 or V _{DD}
SWITCHING CHARACTERISTICS^{2, 4}							
Chip Select to Write Set-Up Time	t _{CS}	180	120		200 150 typ	ns	
Chip Select to Write Hold Time	t _{CH}	0			0	ns	
Data Valid to Write Set-Up Time	t _{DS}	90	60		120 80 typ	ns	
Data Valid to Write Hold Time	t _{DH}	10			10	ns	
Write Pulse Width	t _{WR}	160	100		240 170 typ	ns	

NOTES:

- 1 Full Scale Range (FSR) is 10V for unipolar mode.
- 2 Guaranteed but not production tested.
- 3 Digital input levels should not go below ground or exceed the positive supply voltage, otherwise damage may occur.
- 4 See timing diagram.
- 5 Specified values guarantee functionality. Refer to other parameters for accuracy.

Specifications are subject to change without notice

ABSOLUTE MAXIMUM RATINGS (T_A = +25°C unless otherwise noted)^{1, 2, 3}

V_{DD} to GND 0 to +17 V
 Digital Input Voltage to GND GND –0.5 to V_{DD} +0.5 V
 I_{OUT1}, I_{OUT2} to GND GND –0.5 to V_{DD} +0.5 V
 V_{REF} to GND (2) ±25 V
 V_{RFB} to GND (2) ±25 V
 AGND to DGND ±0.5 V

Storage Temperature –65°C to +150°C
 Lead Temperature (Soldering, 10 seconds) +300°C
 Package Power Dissipation Rating to 75°C
 CDIP, PDIP, SOIC, PLCC 900mW
 Derates above 75°C 12mW/°C

NOTES:

- 1 Stresses above those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation at or above this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.
- 2 Any input pin which can see a value outside the absolute maximum ratings should be protected by Schottky diode clamps (HP5082-2835) from input pin to the supplies. *All inputs have protection diodes* which will protect the device from short transients outside the supplies of less than 100mA for less than 100µs.
- 3 GND refers to AGND and DGND.



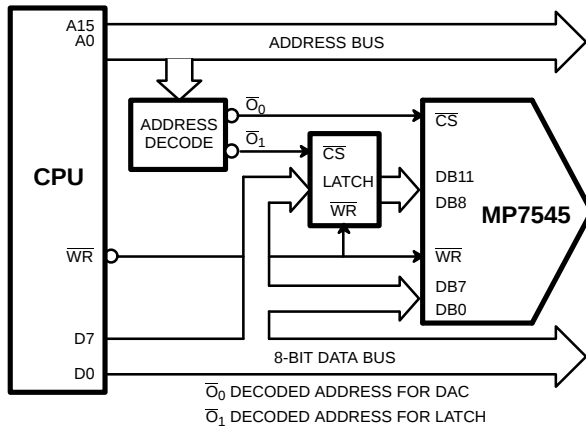


Figure 4. 8-Bit Processor to MP7545 Interface

Figure 4. shows an alternative approach for use with 8-bit processors which have a full 16-bit wide address bus such as 6800, 8080, Z80. This technique uses the 12 lower address lines of the processor address bus to supply data to the DAC, thus each MP7545 connected in this way uses 4k bytes of ad-

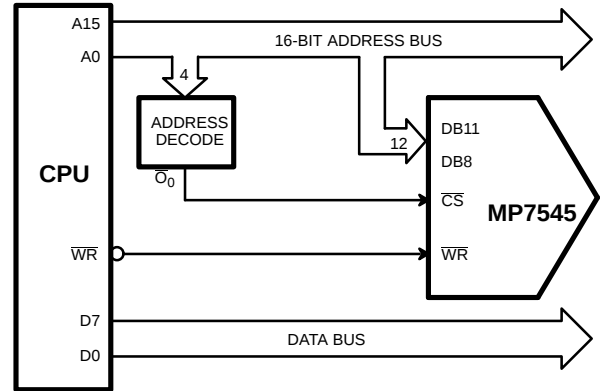
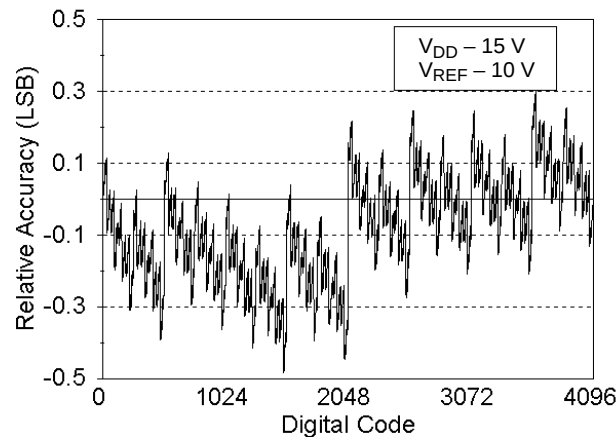


Figure 5. Connecting the MP7545 to 8-Bit Processors via the Address Bus

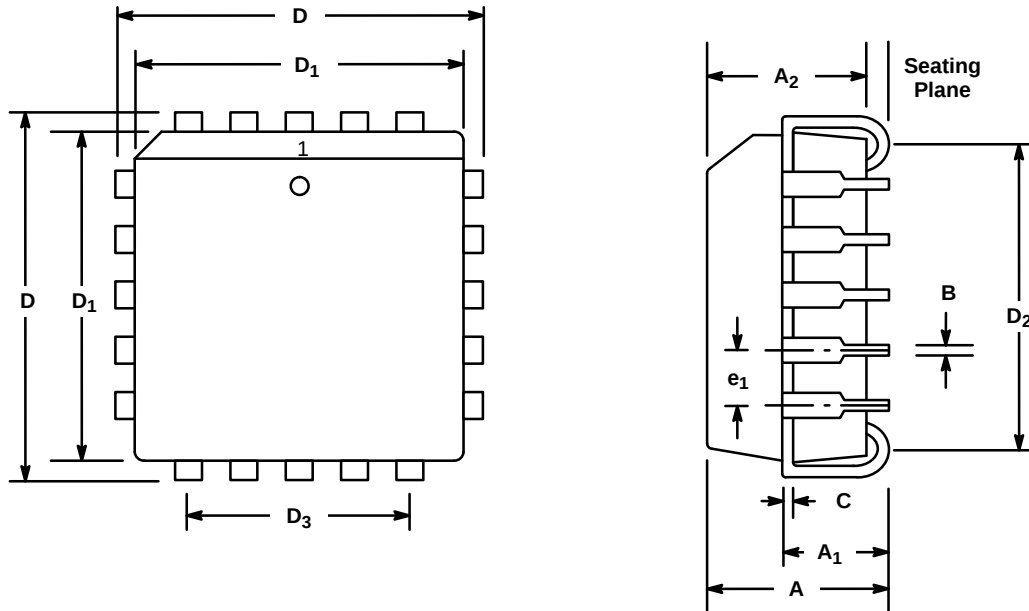
dress locations. Data is written to the DAC using a single memory write instruction. The address field of the instruction is organized so that the lower 12 bits contain the data for the DAC and the upper 4 bits contain the address of the 4k block at which the DAC resides.



Graph 1. Relative Accuracy vs. Digital Code

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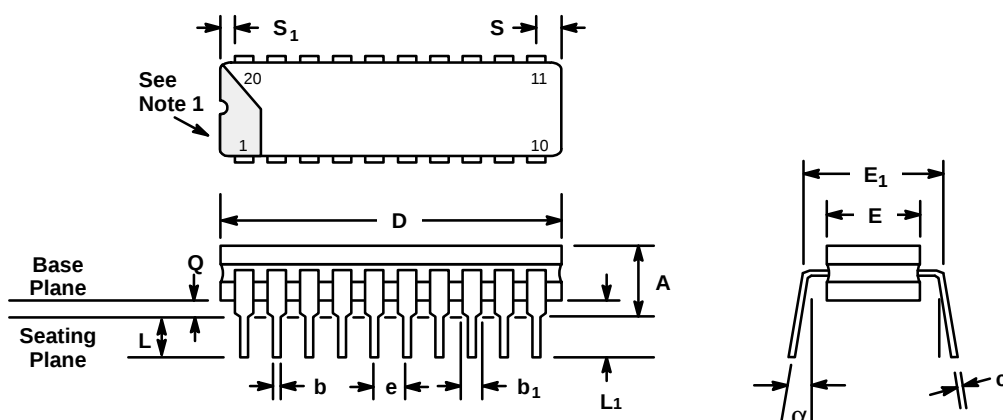
**20 LEAD PLASTIC LEADED CHIP CARRIER
(PLCC)
P20**



SYMBOL	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.165	0.180	4.19	4.57
A ₁	0.100	0.110	2.54	2.79
A ₂	0.148	0.156	3.76	3.96
B	0.013	0.021	0.330	0.533
C	0.008	0.012	0.203	0.305
D	0.385	0.395	9.78	10.03
D ₁ (1)	0.350	0.354	8.89	8.99
D ₂	0.290	0.330	7.37	8.38
D ₃	0.200 Ref		5.08 Ref.	
e ₁	0.050 BSC		1.27 BSC	

Note: (1) Dimension D₁ does not include mold protrusion.
Allowed mold protrusion is 0.254 mm/0.010 in.

**20 LEAD CERAMIC DUAL-IN-LINE
(300 MIL CDIP)
D20**

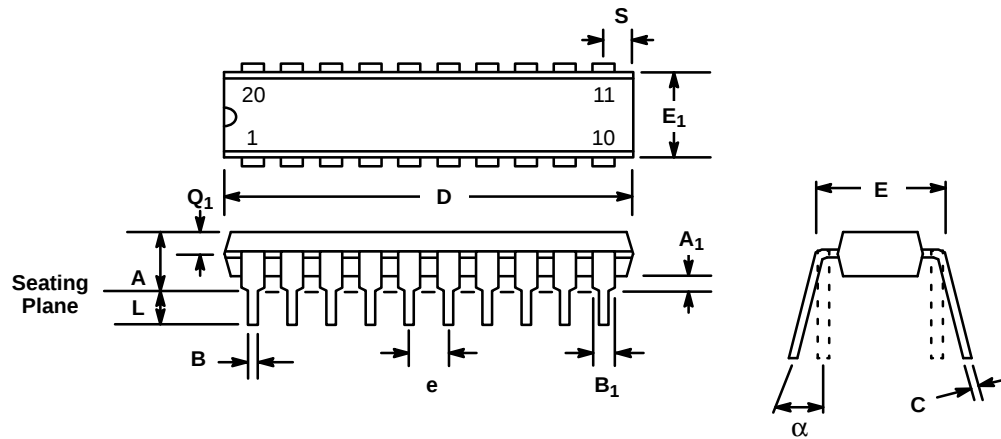


SYMBOL	INCHES		MILLIMETERS		NOTES
	MIN	MAX	MIN	MAX	
A	—	0.200	—	5.08	—
b	0.014	0.023	0.356	0.584	—
b ₁	0.038	0.065	0.965	1.65	2
c	0.008	0.015	0.203	0.381	—
D	—	1.060	—	26.92	4
E	0.220	0.310	5.59	7.87	4
E ₁	0.290	0.320	7.37	8.13	7
e	0.100 BSC		2.54 BSC		5
L	0.125	0.200	3.18	5.08	—
L ₁	0.150	—	3.81	—	—
Q	0.015	0.070	0.381	1.78	3
S	—	0.080	—	2.03	6
S ₁	0.005	—	0.13	—	6
α	0°	15°	0°	15°	—

NOTES

1. Index area; a notch or a lead one identification mark is located adjacent to lead one and is within the shaded area shown.
2. The minimum limit for dimension b₁ may be 0.023 (0.58 mm) for all four corner leads only.
3. Dimension Q shall be measured from the seating plane to the base plane.
4. This dimension allows for off-center lid, meniscus and glass overrun.
5. The basic lead spacing is 0.100 inch (2.54 mm) between centerlines.
6. Applies to all four corners.
7. This is measured to outside of lead, not center.

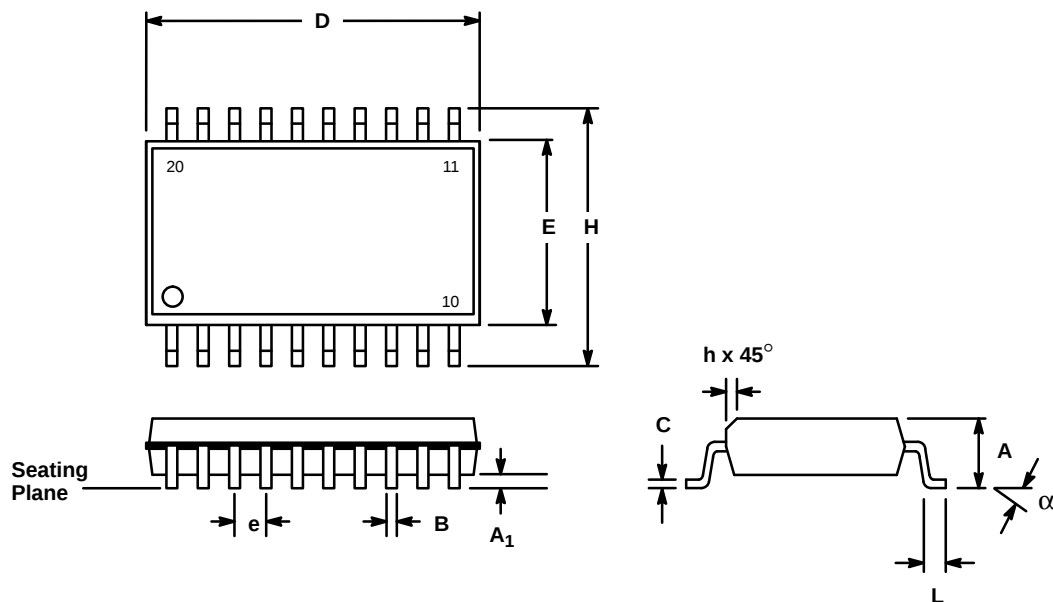
**20 LEAD PLASTIC DUAL-IN-LINE
(300 MIL PDIP)
N20**



SYMBOL	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	—	0.200	—	5.08
A ₁	0.015	—	0.38	—
B	0.014	0.023	0.356	0.584
B ₁ (1)	0.038	0.065	0.965	1.65
C	0.008	0.015	0.203	0.381
D	0.945	1.060	24.0	26.92
E	0.295	0.325	7.49	8.26
E ₁	0.220	0.310	5.59	7.87
e	0.100 BSC		2.54 BSC	
L	0.115	0.150	2.92	3.81
α	0°	15°	0°	15°
Q ₁	0.055	0.070	1.40	1.78
S	0.040	0.080	1.02	2.03

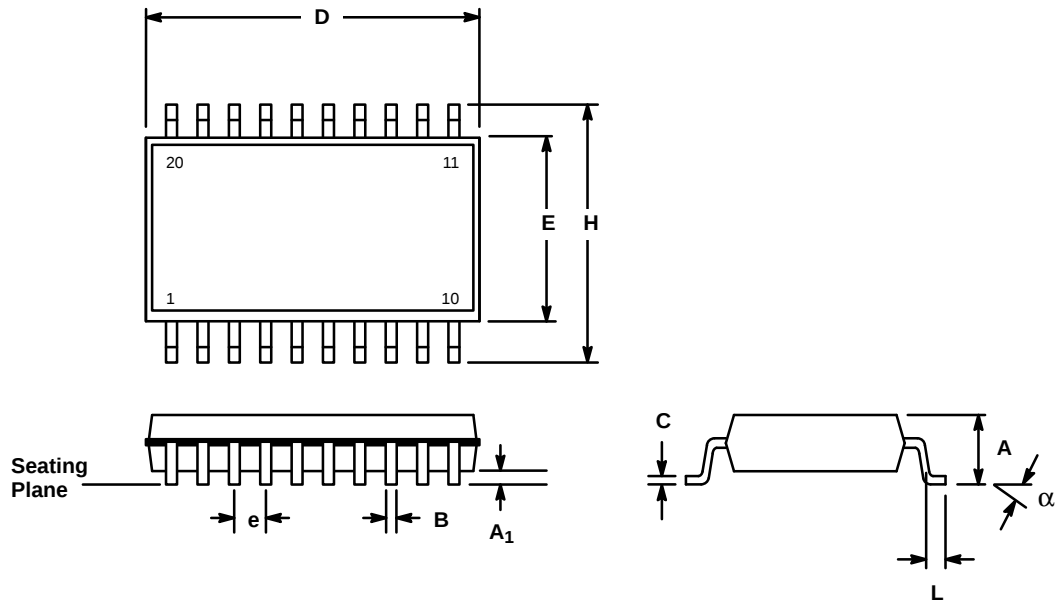
Note: (1) The minimum limit for dimensions B1 may be 0.023" (0.58 mm) for all four corner leads only.

20 LEAD SMALL OUTLINE
(300 MIL JEDEC SOIC)
S20



SYMBOL	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.097	0.104	2.464	2.642
A ₁	0.0050	0.0115	0.127	0.292
B	0.014	0.019	0.356	0.483
C	0.0091	0.0125	0.231	0.318
D	0.500	0.510	12.70	12.95
E	0.292	0.299	7.42	7.59
e	0.050 BSC		1.27 BSC	
H	0.400	0.410	10.16	10.41
h	0.010	0.016	0.254	0.406
L	0.016	0.035	0.406	0.889
α	0°	8°	0°	8°

**20 LEAD SHRINK SMALL OUTLINE PACKAGE
(SSOP)
A20**



SYMBOL	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	1.73	2.05	0.068	0.081
A ₁	0.05	0.21	0.002	0.008
B	0.20	0.40	0.008	0.016
C	0.13	0.25	0.005	0.010
D	7.07	7.40	0.278	0.291
E	5.20	5.38	0.205	0.212
e	0.65 BSC		0.0256 BSC	
H	7.65	8.1	0.301	0.319
L	0.45	0.95	0.018	0.037
α	0°	8°	0°	8°

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